



2858

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TRANSMITTAL FORM <i>(to be used for all correspondence after initial filing)</i>	Application Number	08/838,452
	Filing Date	April 7, 1997
	First Named Inventor	FARNWORTH et al.
	Group Art Unit	2858
	Examiner Name	KARLSEN, E.
Total Number of Pages in This Submission	Attorney Docket Number	91-62.17

ENCLOSURES (check all that apply)		
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<input type="checkbox"/> Response to Missing Parts/ Incomplete Application	Remarks	Enclosed for filing is a Response to the Office Action dated March 2, 2001 having a statutory period for response set to expire on June 4, 2001.
<input type="checkbox"/> Response to Missing Parts under 37 CFR 1.52 or 1.53		

SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT	
Firm or Individual name	Stephen A. Gratton THE LAW OFFICE OF STEPHEN A. GRATTON
Signature	
Date	June 4, 2001

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Typed or printed name	Stephen A. Gratton	Date	June 4, 2001
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UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

WARREN M. FARNWORTH
ALAN G. WOOD
TRUNG TRI DOAN
DAVID R. HEMBREE

Art Unit: 2858

Serial No.: 08/838,452

Filing Date: April 7, 1997

Examiner: Karlsen, E.

Title: TEST APPARATUS FOR TESTING
SEMICONDUCTOR DICE INCLUDING
SUBSTRATE WITH PENETRATION
LIMITING CONTACTS FOR MAKING
ELECTRICAL CONNECTIONS
(AS AMENDED)

Attorney Docket No.: 91-62.17

RESPONSE

June 4, 2001

Assistant Commissioner of Patents
BOX AMENDMENT (NON-FEE)
Washington, D.C. 20231

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JUL 18 2001
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Sir:

This a response to the Office Action dated March 2, 2001
having a statutory period for response set to expire on June
4, 2001. Following is a clean version of the pending claims.

CLEAN VERSION OF PENDING CLAIMS

78. (six times amended) An apparatus for testing a
semiconductor die having a plurality of pads comprising:

a plate;

a substrate on the plate comprising a plurality of
contacts configured to electrically contact the pads;

a clamping mechanism attached to the plate configured to
bias the contacts and the pads together with a force;